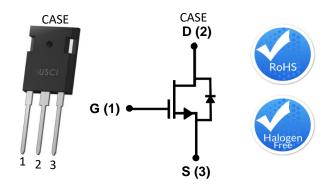


Datasheet

Description

United Silicon Carbide's cascode products co-package its xJ series highperformance SiC JFETs with a cascode optimized MOSFET to produce the only standard gate drive SiC device in the market today. This series exhibits ultra-low gate charge, but also the best reverse recovery characteristics of any device of similar ratings. These devices are excellent for switching inductive loads, and any application requiring standard gate drive.



Part Number	Package	Marking
UJC1210K	TO-247-3L	UJC1210K

Typical Applications

- EV charging
- PV inverters
- Switch mode power supplies
- Power factor correction modules
- Motor drives
- Induction heating

Features

- Max. on-resistance $R_{DS(on)max}$ of $100m\Omega$
- Standard 12V gate drive
- Maximum operating temperature of 150°C
- Excellent reverse recovery
- Low gate charge
- Low intrinsic capacitance
- RoHS compliant

Maximum Ratings

Parameter	Symbol	Test Conditions	Value	Units
Drain-source voltage	V _{DS}		1200	V
Gate-source voltage	V _{GS}	DC	-25 to +25	V
Continuous drain current ¹	1-	T _C = 25°C	21.5	А
continuous drain current	I _D	T _C = 100°C	14	А
Pulsed drain current ²	I _{DM}	T _C = 25°C	66.5	A
Short-circuit withstand time ³	t _{sc}	V _{GS} =15V, V _{CC} <600V	4	μs
Single pulsed avalanche energy ³	E _{AS}	L=15mH, I _{AS} =2.8A	64	mJ
Power dissipation	P _{tot}	T _C = 25°C	113.6	W
Maximum junction temperature	T _{J,max}		150	°C
Operating and storage temperature	T _J , T _{STG}		-55 to 150	°C
Max. lead temperature for soldering, 1/8" from case for 5 Seconds	Т		250	°C

1 Limited by T_{J,max}

2 Pulse width t_p limited by T_{J,max}

3 Starting $T_J = 25^{\circ}C$



Datasheet

Electrical Characteristics (T_J = +25°C unless otherwise specified)

Typical Performance - Static

Parameter	Symbol	Test Conditions	Value			Units
Falameter			Min	Тур	Max	Units
Drain-source breakdown voltage	BV _{DS}	V _{GS} =0V, I _D =1mA	1200			V
Total drain leakage current	I _{DSS}	V _{DS} = 1200V, V _{GS} = 0V, T _J = 25°C		70	500	- μΑ
		V _{DS} = 1200V, V _{GS} = 0V, T _J = 150°C		150		
Total gate leakage current	I _{GSS}	V _{DS} =0V, T _j =25°C, V _{GS} = -20V / +20V		5	100	nA
Drain-source on-resistance	R _{DS(on)}	V _{GS} =12V, I _D =10A, T _J = 25°C		70	100	- mΩ
		V _{GS} =12V, I _D =10A, T _J = 150°C		161		
Gate threshold voltage	V _{G(th)}	$V_{DS} = 5V, I_{D} = 10mA$	4.5	5	5.5	V
Gate resistance	R _G	f = 1MHz, open drain		1.1		Ω

Typical Performance - Reverse Diode

Parameter	Symbol	Test Conditions	Value			
			Min	Тур	Max	Units
Diode continuous forward current ¹	۱ _s	T _C = 25°C			21.5	А
Diode pulse current ²	I _{S,pulse}	T _C = 25°C			66.5	А
Forward voltage	V _{FSD}	V _{GS} = 0V, I _F =10A, T _J = 25°C		1.4	2	v
		V _{GS} = 0V, I _F = 10A, T _J =150°C		2		
Reverse recovery charge	Q _{rr}	V_{R} =800V, I _F =14A, V_{GS} =0V, $R_{G_{EXT}}$ = 22 Ω		112		nC
Reverse recovery time	t _{rr}	di/dt=1550A/μs, Τ _J = 25°C		34		ns
Reverse recovery charge	Q _{rr}	V_{R} =800V, I _F =14A, V_{GS} =0V, $R_{G_{EXT}}$ = 22 Ω		127		nC
Reverse recovery time	t _{rr}	di/dt=1550A/µs, Tյ = 150°C		36		ns



Datasheet

Typical Performance - Dynamic

Parameter	symbol	Test Conditions	Value			Units
	Symbol	Test conditions	Min	Тур	Max	Onits
Input capacitance	C _{iss}	V _{DS} = 100V,		2214		
Output capacitance	C _{oss}	$V_{GS} = 0V,$		106		pF
Reverse transfer capacitance	C _{rss}	f = 100kHz		3.5		
Effective output capacitance, energy related	C _{oss(er)}	$V_{DS} = 0V \text{ to } 800V,$ $V_{GS} = 0V$		57		pF
Effective output capacitance, time related	C _{oss(tr)}	$V_{DS} = 0V \text{ to } 800V,$ $V_{GS} = 0V$		100		pF
C _{oss} stored energy	E _{oss}	$V_{DS} = 800V, V_{GS} = 0V$		18.5		μ
Total gate charge	Q _G	N 000V L 144		47.5		nC
Gate-drain charge	Q _{GD}	V_{DS} =800V, I_{D} = 14A, V_{GS} =0V to 12V		15		
Gate-source charge	Q _{GS}	V _{GS} =0V to 12V		15		
Turn-on delay time	t _{d(on)}			32		- ns
Rise time	t _r	- V _{DS} =800V, I _D =14A, Gate $-Driver =0V to +12V,Turn-on RG.EXT = 2\Omega,$		17		
Turn-off delay time	t _{d(off)}			94		
Fall time	t _f	Turn-off $R_{G,EXT} = 22\Omega$		19		
Turn-on energy	E _{ON}	Inductive Load, FWD: UJ2D1210T T ₁ = 25°C		266		
Turn-off energy	E _{OFF}			56		μ
Total switching energy	E _{TOTAL}			322		
Turn-on delay time	t _{d(on)}			32		
Rise time	t _r	V_{DS} =800V, I_{D} =14A, Gate		21		- ns
Turn-off delay time	t _{d(off)}	Driver =0V to +12V, Turn-on $R_{G,EXT} = 2\Omega$, Turn-off $R_{G,EXT} = 22\Omega$		102		
Fall time	t _f			21		
Turn-on energy	E _{ON}	Inductive Load, FWD: UJ2D1210T T ₁ = 150°C		290		
Turn-off energy	E _{OFF}			78		μ
Total switching energy	E _{TOTAL}			368		

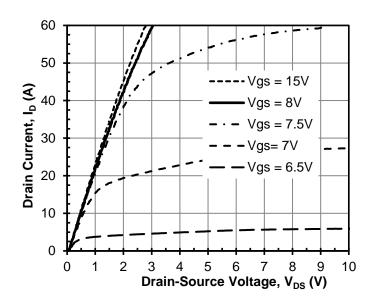
Thermal Characteristics

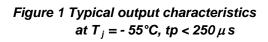
Parameter	symbol	Test Conditions	Value			Units
			Min	Тур	Max	Units
Thermal resistance, junction-to-case	$R_{\theta JC}$			0.85	1.1	°C/W

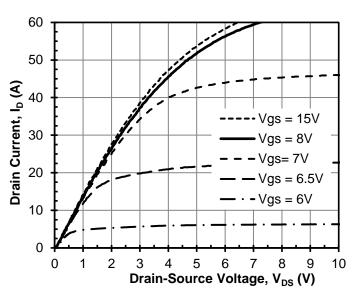


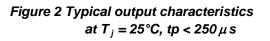
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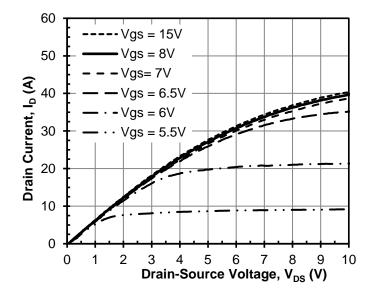
Typical Performance Diagrams

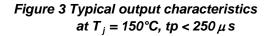


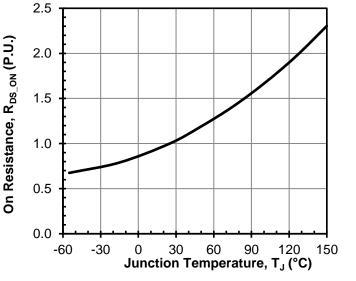


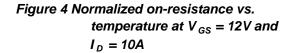






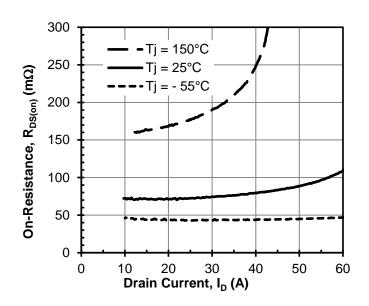


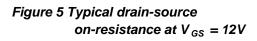


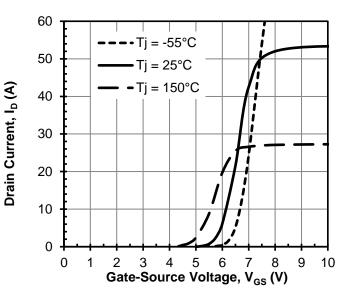


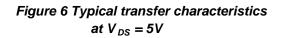


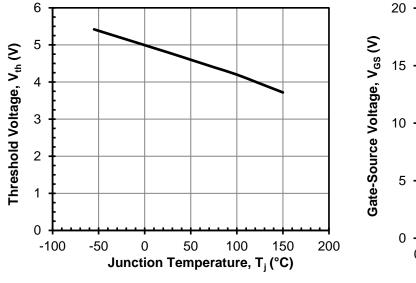
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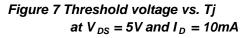












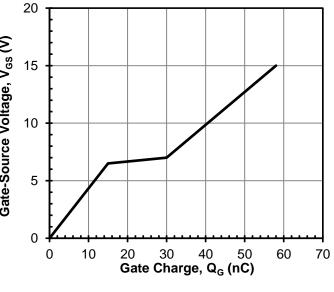


Figure 8 Typical gate charge at $V_{DS} = 800V$ and $I_D = 14A$



Vgs = 0V

Vgs= 5V

Vgs = 8V

-3

Vgs = 15V

0

-5

10

-15

-20

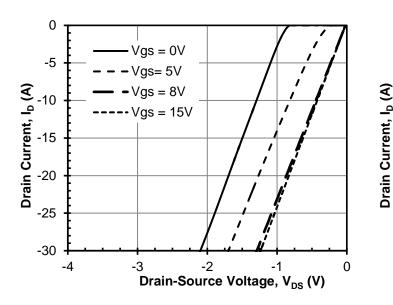
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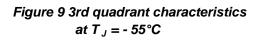
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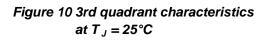
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0



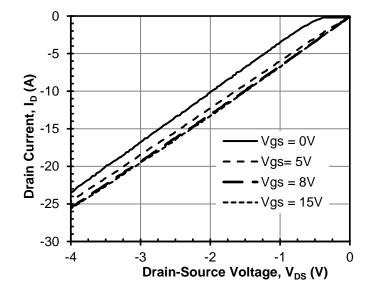


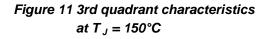


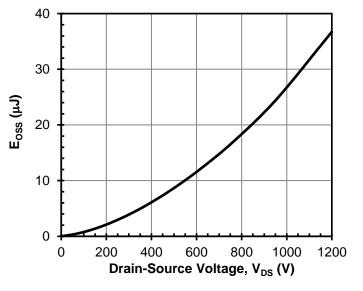
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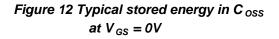
Drain-Source Voltage, V_{DS} (V)

-1



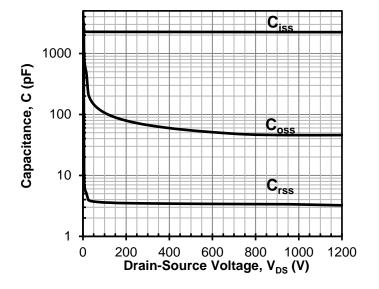


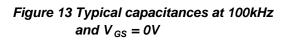






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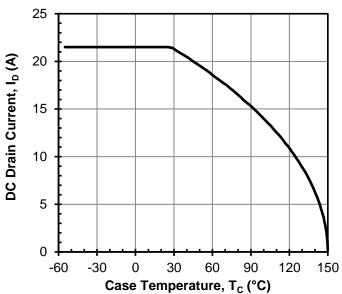


Figure 14 DC drain current derating

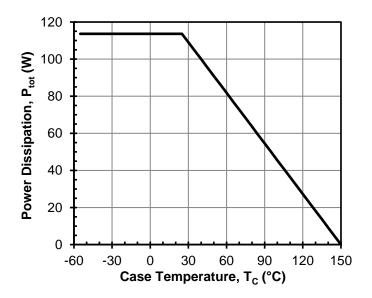


Figure 15 Total power dissipation

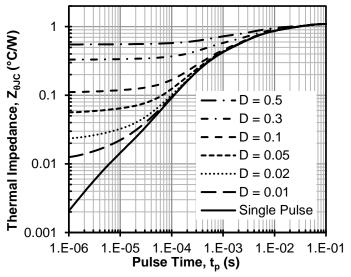


Figure 16 Maximum transient thermal impedance



Datasheet

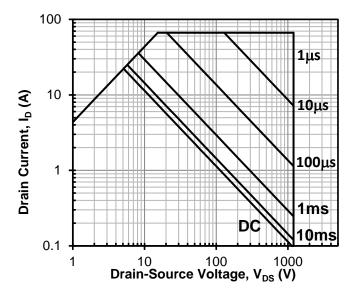


Figure 17 Safe operation area $T_c = 25^{\circ}$ C, D = 0, Parameter t_p

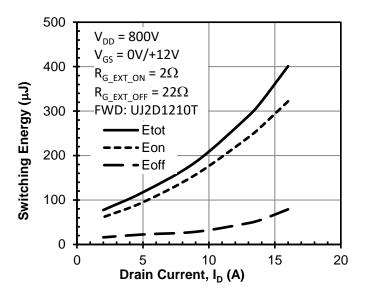
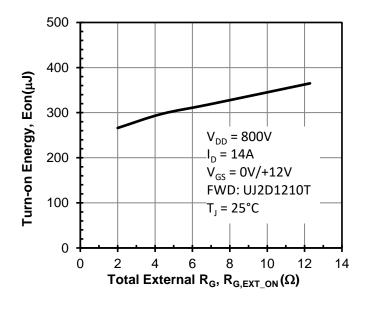
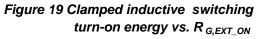


Figure 18 Clamped inductive switching energy vs. drain current at $T_J = 25$ °C





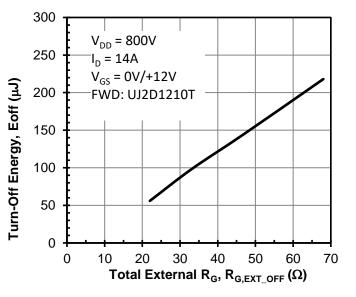


Figure 20 Clamped inductive switching turn-off energy vs. R_{G,EXT_OFF}



Datasheet

Applications Information

SiC cascodes are enhancement-mode power siwtches formed by a high-voltage SiC depletion-mode JFET and a low-voltage silicon MOSFET connected in series. The silicon MOSFET serves as the control unit while the SiC JFET provides high voltage blocking in the off state. This combination of devices in a single package provides compatibility with standard gate drivers and offers superior performance in terms of low on-resistance (R_{DS(on)}), output capacitance (Coss), gate charge (Qg), and reverse recovery charge (Qrr) leading to low conduction and switching losses. The SiC cascodes also provide excellent reverse conduction capability eliminating the need for an external anti-parallel diode.

Like other high performance power switches, proper PCB layout design to minimize circuit parasitics is strongly recommended due to the high dv/dt and di/dt rates. An external gate resistor is recommended when the cascode is working in the diode mode in order to achieve the optimum reverse recover performance. For more information on cascode operation, see www.unitedsic.com.

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